

<b>STN</b>	<b>Mocninový model. Testy dobrej zhody a metódy odhadu parametrov.</b>	<b>STN EN 61710</b>  01 0650
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Táto norma obsahuje anglickú verziu európskej normy.  
This standard includes the English version of the European Standard.

Táto norma bola oznámená vo Vestníku ÚNMS SR č. 12/13

Obsahuje: EN 61710:2013, IEC 61710:2013

English version

**Power law model -  
Goodness-of-fit tests and estimation methods  
(IEC 61710:2013)**

Modèle de loi en puissance -  
Essais d'adéquation et méthodes  
d'estimation des paramètres  
(CEI 61710:2013)

Potenzgesetz-Modell -  
Anpassungstests und Schätzverfahren  
(IEC 61710:2013)

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## Foreword

The text of document 56/1500/FDIS, future edition 2 of IEC 61710, prepared by IEC/TC 56 "Dependability" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 61710:2013.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2014-03-26
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IEC 61703	NOTE	Harmonised as EN 61703.
IEC 61164:2004	NOTE	Harmonised as EN 61164:2004 (not modified).

## **Annex ZA** (normative)

### **Normative references to international publications with their corresponding European publications**

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050-191	1990	International Electrotechnical Vocabulary (IEV) - Chapter 191: Dependability and quality of service	-	-



# INTERNATIONAL STANDARD

# NORME INTERNATIONALE



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**Power law model – Goodness-of-fit tests and estimation methods**

**Modèle de loi en puissance – Essais d'adéquation et méthodes d'estimation des paramètres**





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Edition 2.0 2013-05

# INTERNATIONAL STANDARD

# NORME INTERNATIONALE



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**Power law model – Goodness-of-fit tests and estimation methods**

**Modèle de loi en puissance – Essais d'adéquation et méthodes d'estimation des paramètres**

INTERNATIONAL  
ELECTROTECHNICAL  
COMMISSION

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

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**POWER LAW MODEL –  
GOODNESS-OF-FIT TESTS  
AND ESTIMATION METHODS**
**FOREWORD**

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International Standard IEC 61710 has been prepared by IEC technical committee 56: Dependability.

This second edition cancels and replaces the first edition, published in 2000, and constitutes a technical revision.

The main changes with respect to the previous edition are listed below:

- the inclusion of an additional Annex C on Bayesian estimation for the power law model.

The text of this standard is based on the following documents:

FDIS	Report on voting
56/1500/FDIS	56/1508/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

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## INTRODUCTION

This International Standard describes the power law model and gives step-by-step directions for its use. There are various models for describing the reliability of repairable items, the power law model being one of the most widely used. This standard provides procedures to estimate the parameters of the power law model and to test the goodness-of-fit of the power law model to data, to provide confidence intervals for the failure intensity and prediction intervals for the length of time to future failures. An input is required consisting of a data set of times at which relevant failures occurred, or were observed, for a repairable item or a set of copies of the same item, and the time at which observation of the item was terminated, if different from the time of final failure. All output results correspond to the item type under consideration.

Some of the procedures can require computer programs, but these are not unduly complex. This standard presents algorithms from which computer programs should be easy to construct.

## POWER LAW MODEL – GOODNESS-OF-FIT TESTS AND ESTIMATION METHODS

### 1 Scope

This International Standard specifies procedures to estimate the parameters of the power law model, to provide confidence intervals for the failure intensity, to provide prediction intervals for the times to future failures, and to test the goodness-of-fit of the power law model to data from repairable items. It is assumed that the time to failure data have been collected from an item, or some identical items operating under the same conditions (e.g. environment and load).

### 2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-191:1990, *International Electrotechnical Vocabulary (IEV) – Chapter 191: Dependability and quality of service*

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